

Powder Diffraction

| | | |
|---|--|----|
| Deane K. Smith, Gregory J. McCarthy, Jan W. Visser, Brian H. O'Connor, Hideo Toraya | Editorial: Reitveld analysis and data for the powder diffraction file | 1 |
| N. R. Khasanova, A. V. Mironov, and E. V. Antipov | Incommensurately modulated structure of $\text{Bi}_2\text{Sr}_2\text{Eu}_{1.3}\text{Ce}_{0.7}\text{Cu}_2\text{O}_{10.17}$ refined from X-ray powder data | 2 |
| V. Stepanov, B. Bondars | The automation of DRON diffractometers | 7 |
| W. Wong-Ng, C. S. Choi, and L. P. Cook | Microstructural effect on corrosion of tungsten in SF_6 environment | 8 |
| Paolo Ballirano, Adriana Maras, Peter R. Buseck, Su Wang, and Ann M. Yates | Improved powder X-ray data for cancrinites II: Liottite and sacrofanite | 13 |
| Patricia Bénard, Jean Paul Auffrédic, and Daniel Louër | An X-ray powder diffraction study of amine zinc hydroxide nitrate | 20 |
| Walter N. Schreiner | A standard test method for the determination of RIR values by X-ray diffraction | 25 |
| Naoaki Sudo, Hiroo Hashizume, and Carlos A. M. Carvalho | Test of maximum-entropy methods to solve a small structure <i>ab initio</i> from powder diffraction data | 34 |
| Cem Basceri, A. Cuneyt Tas, and Muharrem Timucin | Characterization of new solid solution phases in $(\text{Y,Ca})(\text{Cr,Co})\text{O}_3$ system | 40 |
| O. Greis, R. Ziel, B. Breidenstein, A. Haase, and T. Petzel | Structural data of the tysonite-type superstructure modification $\beta\text{-PrF}_3$ from X-ray powder and electron single-crystal diffraction | 44 |
| Steve J. Chipera, David L. Bish | Multireflection RIR and intensity normalizations for quantitative analyses: Applications to feldspars and zeolites | 47 |
| Winnie Wong-Ng | Structures and X-ray diffraction patterns of compounds in the Sr-Nd-Cu-O system | 56 |
| | International Report | |
| | Calendar of Meetings | 67 |
| | Computer Comments | 68 |
| | Cumulative Author Index | 74 |



Volume 10 Number 1 March 1995

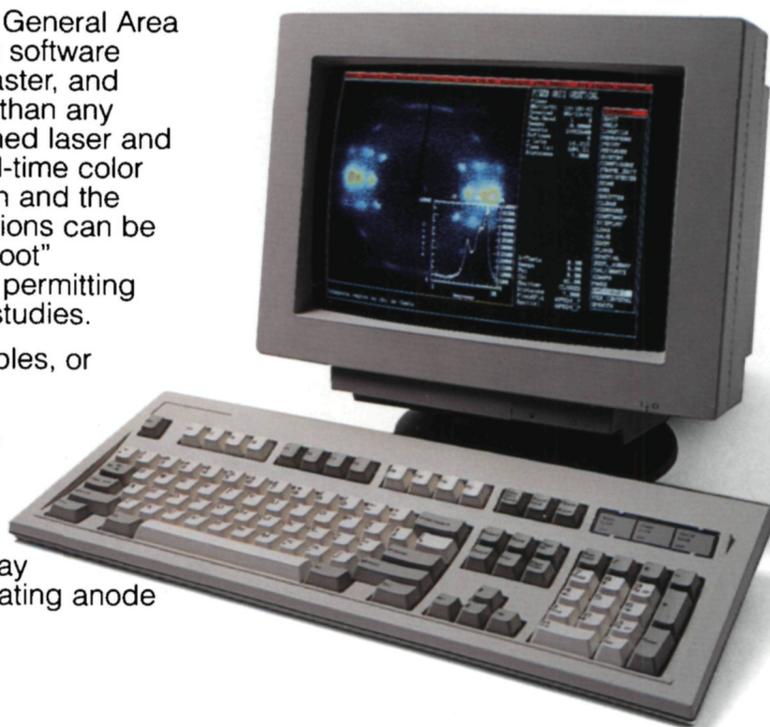
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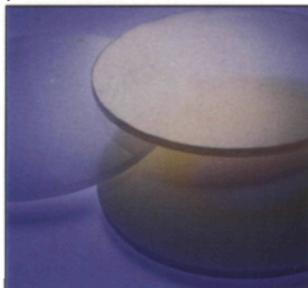
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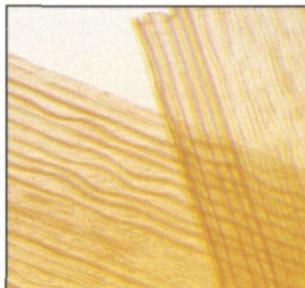
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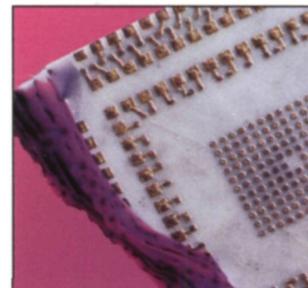
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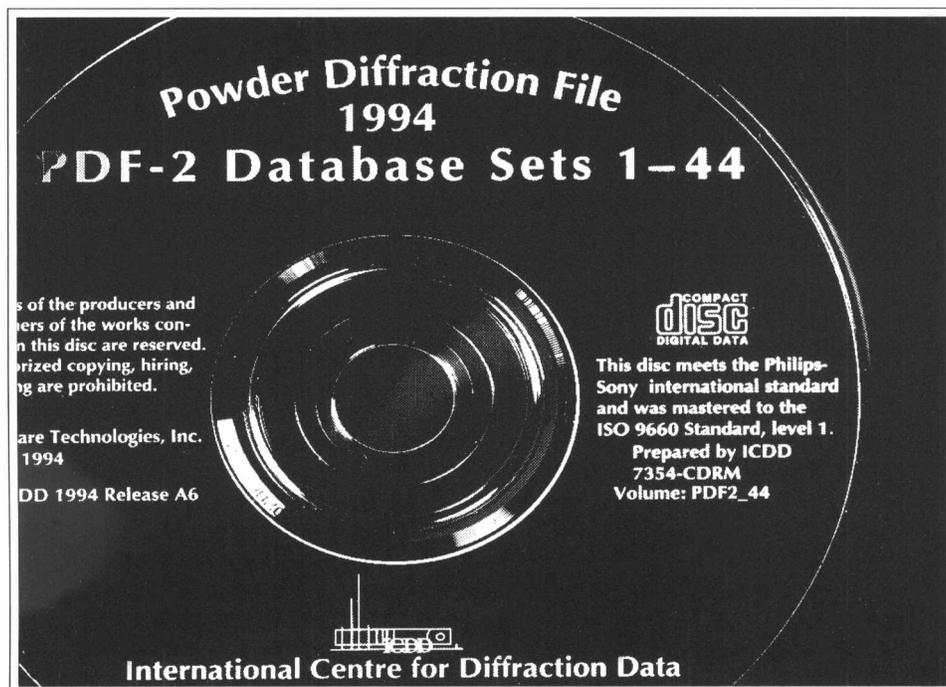
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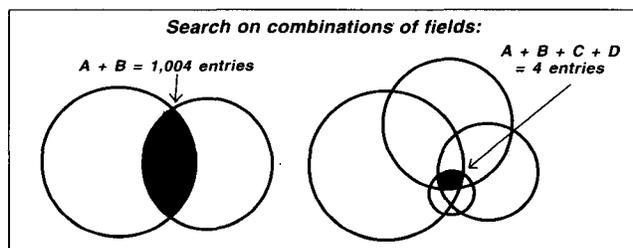
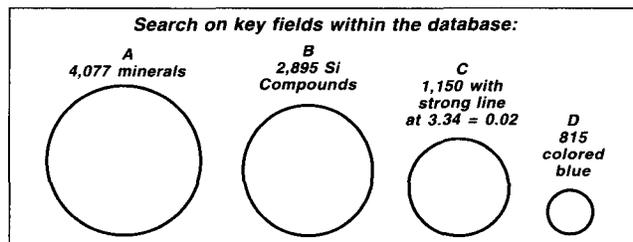
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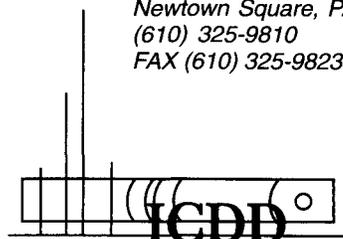


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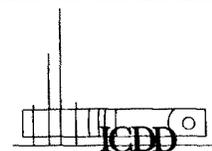
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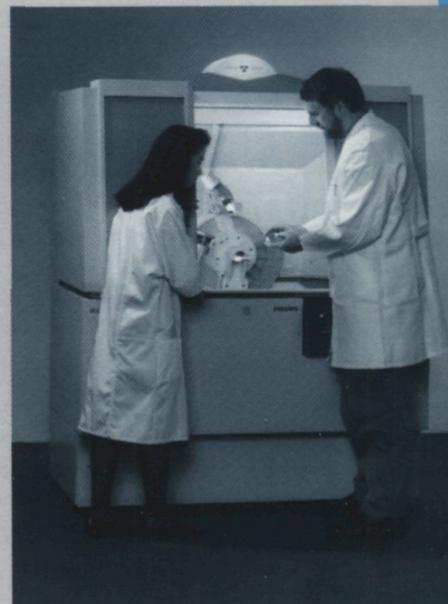
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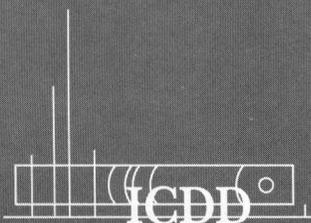
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